

Notice of References Cited	Application/Control No. 10/052,464	Applicant(s)/Patent Under Reexamination IWAMURA, KEIICHI	
	Examiner Eleni A. Shiferaw	Art Unit 2136	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,748,533 B1	06-2004	Wu et al.	713/176
	B	US-2004/0034781 A1	02-2004	Natarajan, Balas K.	713/181
	C	US-2004/0059918 A1	03-2004	Xu, Changsheng	713/176
	D	US-6,707,774 B1	03-2004	Kuroda et al.	369/53.21
	E	US-6,785,814 B1	08-2004	Usami et al.	713/176
	F	US-6,523,114 B1	02-2003	Barton, James M.	713/176
	G	US-6,438,692 B2	08-2002	Kato et al.	713/176
	H	US-2004/0004115 A1	01-2004	Epstein, Michael A.	235/375
	I	US-6,754,365 B1	06-2004	Wen et al.	382/100
	J	US-2004/0032611 A1	02-2004	Daly et al.	358/1.13
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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